Notice of References Cited				Application/01/01/01/01/01/01/01/01/01/01/01/01/01/	Application/Control No.		Applicant(s)/Patent Under Reexamination NIE ET AL.	
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U.S. PATENT DOCUMENTS								
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name			Classification	
*	Α	US-2002/0034246 A1	03-2002	Yamada et al.			375/240.03	
	В	US-						
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	Е	US-						
	F	US-						
	G	US-						
	Н	US-						
	I	US-						
	J	US-						
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FOREIGN PATENT DOCUMENTS								
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name		Classification	
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